(2) Brief BIO  
  
James Chien-Mo Li received his BSEE degree in 1993 from National Taiwan University, Taipei, Taiwan.  He received his MSEE and PhD degrees in electrical engineering from Stanford University in 1997 and 2002 respectively.      He is currently a professor of Graduate Institute of Electronics Engineering, National Taiwan University.  His research interest includes test generation, low power testing, and diagnosis.    
  
(3) 目前專注技術項目  
IC defect diagnosis , yield improvement